# MOSFET - Power, Single N-Channel, TOLL

40 V, 0.57 mΩ, 300 A

### **NVBLS0D5N04C**

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- AEC-Q101 Qualified and PPAP Capable
- Small Footprint (TOLL) for Compact Design
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	40	V
Gate-to-Source Voltage	9		$V_{GS}$	+20/-16	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	300	Α
Current R <sub>0JC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		300	
Power Dissipation	State	T <sub>C</sub> = 25°C	$P_{D}$	198.4	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		97.4	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	65	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		46	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	4.3	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		2.1	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	4700	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			IS	170	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 55 A, L = 1 mH)			E <sub>AS</sub>	1512	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.77	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	35	

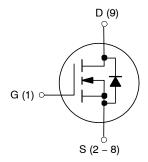
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted. Current is limited by bondwire configuration.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



#### ON Semiconductor®

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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
40 V	0.57 m $\Omega$ @ 10 V	300 A



**N-CHANNEL MOSFET** 



H-PSOF8L CASE 100CU

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NVBLS0D5N04CTXG	H-PSOF8L (Pb-Free)	2000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

Table 1. ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions		Min	Тур	Max	Units
OFF CHARACTERISTICS	•	•					
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$I_D = 250 \mu\text{A},  V_{GS} = 0 \text{V}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /T <sub>J</sub>				21.3		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 40 V, V <sub>GS</sub> = 0 V	T <sub>J</sub> = 25°C			1	μΑ
			T <sub>J</sub> = 175°C			1	mA
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> =	= +20/–16 V			±100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 475 μΑ	2	2.8	4	V
Threshold Temperature Coefficient	V <sub>GS(th)</sub> /T <sub>J</sub>				-7.4		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V, I	<sub>D</sub> = 50 A		0.5	0.57	mΩ
CHARGES, CAPACITANCES & GATE RE	SISTANCE			•			
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1 MHz			12600		pF
Output Capacitance	C <sub>oss</sub>	1			6705		pF
Reverse Transfer Capacitance	C <sub>rss</sub>	1			227		pF
Gate Resistance	Rg	V <sub>GS</sub> = 0.5 V, f	= 1 MHz		1.8		Ω
Total Gate Charge	Q <sub>G(tot)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 20 V, I <sub>D</sub> = 50 A			185		nC
Threshold Gate Charge	Q <sub>G(th)</sub>	V <sub>GS</sub> = 0 to	2 V		22		nC
Gate-to-Source Gate Charge	Q <sub>gs</sub>	V <sub>DD</sub> = 32 V, I	<sub>D</sub> = 50 A		48		nC
Gate-to-Drain "Miller" Charge	Q <sub>gd</sub>				38		nC
Plateau Voltage	$V_{GP}$	1			4.2		V
SWITCHING CHARACTERISTICS (Note 5	)						
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{GS} = 10 \text{ V}, V_{E}$ $I_{D} = 50 \text{ A}, R_{G}$	<sub>DD</sub> = 20 V,		40		ns
Turn-On Rise Time	t <sub>r</sub>	$I_D = 50 \text{ A}, H_G$	EN = 6 Ω		84		ns
Turn-Off Delay Time	t <sub>d(off)</sub>	1			164		ns
Turn-Off Fall Time	t <sub>f</sub>	1			81		ns
DRAIN-SOURCE DIODE CHARACTERIS	TICS	•			-	-	-
Source-to-Drain Diode Voltage	$V_{SD}$	I <sub>SD</sub> = 50 A, V	<sub>GS</sub> = 0 V		0.76	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$V_{GS} = 0 \text{ V, } dI_S/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 50 \text{ A}$			108		ns
Charge Time	ta				62		ns
Discharge Time	t <sub>b</sub>				46		ns
Reverse Recovery Charge	Q <sub>rr</sub>	1			288		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures

#### **TYPICAL CHARACTERISTICS**

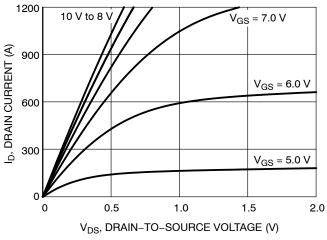
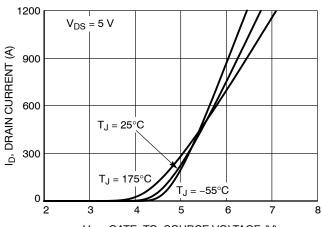


Figure 1. On-Region Characteristics



V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V) Figure 2. Transfer Characteristics

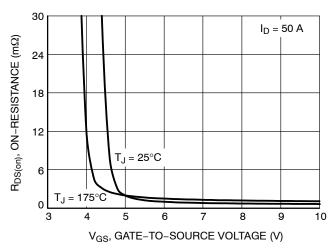


Figure 3. On-Resistance vs. Gate-to-Source Voltage

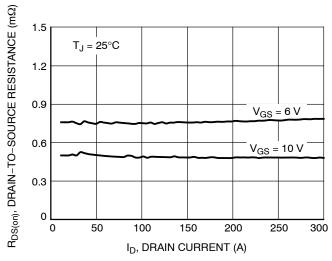


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

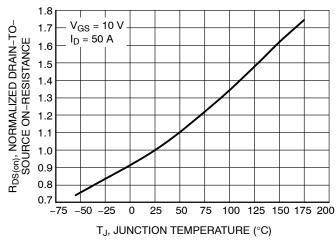


Figure 5. On–Resistance Variation with Temperature

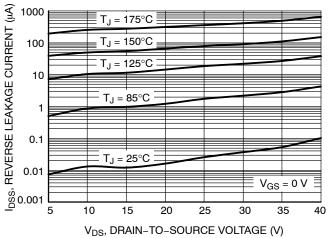


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

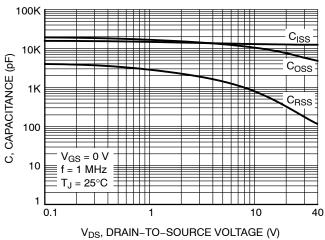


Figure 7. Capacitance Variation

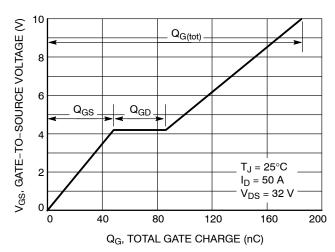


Figure 8. Gate-to-Source Voltage vs. Total Charge

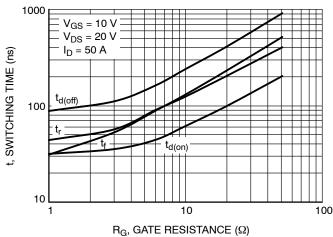


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

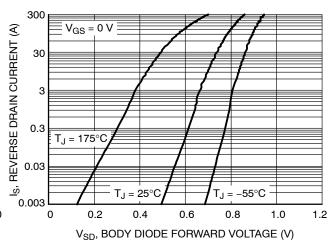


Figure 10. Diode Forward Voltage vs. Current

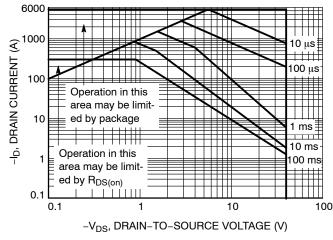


Figure 11. Forward Biased Safe Operating Area

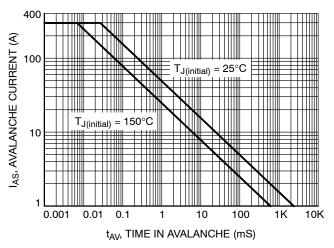


Figure 12. Maximum Drain Current vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

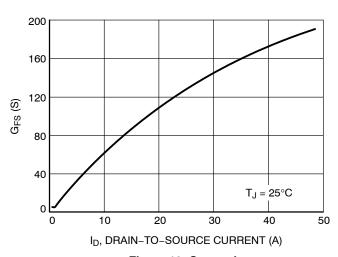


Figure 13.  $G_{FS}$  vs.  $I_D$ 

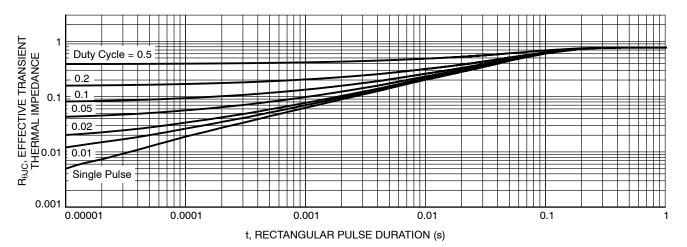
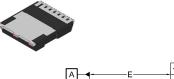


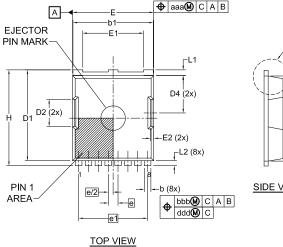
Figure 14. Transient Thermal Impedance

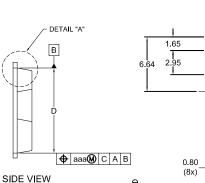


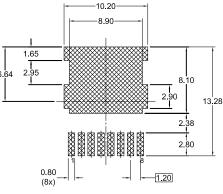


#### H-PSOF8L 11.68x9.80 CASE 100CU **ISSUE C**

#### **DATE 22 MAY 2023**



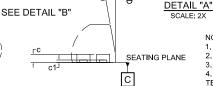




#### LAND PATTERN RECOMMENDATION

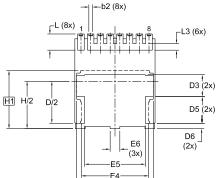
\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

## Α1 eee C FRONT VIEW



SCALE: 2X





BOTTOM VIEW

- 1. PACKAGE STANDARD REFERENCE: JEDEC MO-299, ISSUE A. 2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 3. CONTROLLING DIMENSION: MILLIMETERS. 4. COPLANARITY APPLIES TO THE EXPOSED WELL AS THE
- 5. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
- 6. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE
- LOWEST POINT ON THE PACKAGE BODY.

DIM	MILLIMETERS		
D	MIN.	NOM.	MAX.
Α	2.20	2.30	2.40
A1	1.70	1.80	1.90
b	0.70	0.80	0.90
b1	9.70	9.80	9.90
b2	0.35	0.45	0.55
С	0.40	0.50	0.60
c1	0.10	_	_
D	10.28	10.38	10.48
D/2	5.09	5.19	5.29
D1	10.98	11.08	11.18
D2	3.20	3.30	3.40
D3	2.60	2.70	2.80
D4	4.45	4.55	4.65
D5	3.20	3.30	3.40
D6	0.55	0.65	0.75
Е	9.80	9.90	10.00
E1	7.30	7.40	7.50
E2	0.30	0.40	0.50
E3	9.36	9.46	9.56

ДІМ	MILLIMETERS		
Diw	MIN.	NOM.	MAX.
E4	8.20	8.30	8.40
E5	7.40	7.50	7.60
E6	1.10	1.20	1.30
е		1.20 BSC	;
e/2	(	0.60 BSC	;
e1		3.40 BSC	
Н	11.58	11.68	11.78
H/2	5.74	5.84	5.94
H1	7.15 BSC		
L	1.90	2.00	2.10
L1	0.60	0.70	0.80
L2	0.50	0.60	0.70
L3	0.70	0.80	0.90
θ	0°	_	12°
aaa	0.20		
bbb	0.25		
ccc	0.20		
ddd	0.20		
eee	0.10		

#### **GENERIC MARKING DIAGRAM\***

**AYWWZZ** XXXXXXX XXXXXXX

Α = Assembly Location

= Year

WW = Work Week

= Assembly Lot Code ZΖ XXXX = Specific Device Code \*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

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**DESCRIPTION:** 

H-PSOF8L 11.68x9.80

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